EXAMINER Haid : Phan \*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Hrl WIR Patent Abstracts of Japan, Vol. 2003, No. 06, June 3, 2003 (See JP 2003 - 045676 above)
Patent Abstracts of Japan, Vol. 2000, No. 02, February 29, 2000 (See JP 11-329749 above)

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